

# Dual/Quad Low Noise High Speed Precision Op Amps

#### DESCRIPTION

The LT1124M/883 dual and LT1125M/883 quad are high performance op amps that offer higher gain, slew rate, and bandwidth than the industry standard OP-27 and competing OP-270/OP-470 op amps. In addition, the LT1124M/883 and LT1125M/883 have lower  $I_B$  and  $I_{OS}$  than the OP27; lower  $V_{OS}$  and noise than the OP-270/OP-470.

In the design, processing, and testing of these devices, particular attention has been paid to the optimization of the entire distribution of several key parameters. Power comsumption of the LT1124M/883 is one half of two OP-27s.

For a decompensated version of these devices, with three times higher slew rate and bandwidth, please see the LT1126/LT1127 data sheet.

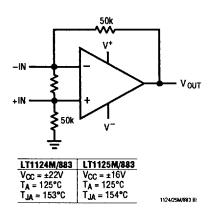
The devices are processed to the requirements of MIL-STD-883 Class B to yield circuits usable in precision military applications.

## ABSOLUTE MAXIMUM RATINGS

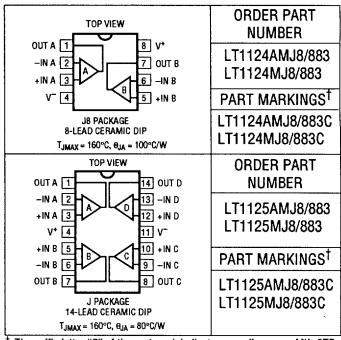
Supply Voltage ±22	2V
Input Voltage Equal to Supply Voltage	
Output Short Circuit Duration Indefini	ite
Differential Input Current (Note 1)±25m	nΑ
Operating Temperature Range	
LT1124AM/883, LT1124M/883	
LT1125AM/883, LT1125M/88355°C to 125°	°C
Storage Temperature Range	
All Grades65°C to 150°	°C
Lead Temperature (Soldering, 10 sec.) 300	°C

Protected by U.S. patents 4,775,884 and 4,837,496.

### BURN-IN CIRCUIT



## PACKAGE/ORDER INFORMATION



<sup>†</sup> The suffix letter "C" of the part mark indicates compliance per MIL-STD-883, para 1.2.1.1.



Information furnished by Linear Technology Corporation is believed to be accurate and reliable. However, no responsibility is assumed for its use. Linear Technology Corporation makes no representation that the interconnection of circuits as described herein will not infringe on existing patent rights.

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TABLE 1: ELECTRICAL CHARACTERISTICS  $VS = \pm 15V$ ,  $T_A = 25$ °C, unless otherswise noted. (Note 1)

				LT1124AM/883 LT1125AM/883			LT1124M/883 LT1125M/883			SUB-	
SYMBOL	PARAMETER	CONDITIONS	NOTES	MIN	TYP	MAX	MIN	TYP	MAX	GROUP	UNITS
Vos	Input Offset Voltage	LT1124 LT1125				70 90			100 140	4	μV μV
los	Input Offset Current	LT1124 LT1125				15 20			20 30	1	nA nA
I <sub>B</sub>	Input Bias Current					±20			±30	1	nA
en	Input Noise Voltage	0.1Hz to 10Hz	3			200					nV <sub>P-P</sub>
	Input Noise Voltage Density	f <sub>O</sub> = 10Hz f <sub>O</sub> = 1000Hz		,		5.5 4.2			5.5 4.2		nV/√Hz nV/√Hz
V <sub>CM</sub>	Input Voltage Range		4	±12.0			±12.0				٧
CMRR	Common-Mode Rejection Ratio	V <sub>CM</sub> = ±12V		112			106			1	dB
PSRR	Power Supply Rejection Ratio	$V_S = \pm 4V \text{ to } \pm 18V$		116			110			1	dB
A <sub>VOL</sub>	Large-Signal Voltage Gain	$R_L \ge 10k$ , $V_0 = \pm 10V$ $R_L \ge 2k$ , $V_0 = \pm 10V$		5.0 2.0			3.0 1.5			4	V/μV V/μV
V <sub>OUT</sub>	Maximum Output Voltage Swing	R <sub>L</sub> ≥ 2k		±13.0			±12.5			4	V
SR	Slew Rate	R <sub>L</sub> ≥ 2k	2	3.0			2.7			7	V/µs
I <sub>S</sub>	Supply Current per Amplifier					2.75			2.75	1	mA

#### $V_S = \pm 15V$ , $-55^{\circ}C \le T_A \le 125^{\circ}C$ , unless otherswise noted.

Vos	Input Offset Voltage	LT1124 LT1125			170 190		250 290	2,3 2,3	μV μV
Ios	Input Offset Current	LT1124 LT1125			45 55		60 70	2,3 2,3	nA nA
l <sub>B</sub>	Input Bias Current				±55		±70	2,3	nA
V <sub>CM</sub>	Input Voltage Range		4	±11.3		±11.3	•		v
CMRR	Common-Mode Rejection Ratio	$V_{CM} = \pm 11.3V$		106		100		2,3	dB
PSRR	Power Supply Rejection Ratio	$V_S = \pm 4V$ to $\pm 18V$		110		104		2,3	dB
A <sub>VOL</sub>	Large-Signal Voltage Gain	$R_L \ge 10k$ , $V_0 = \pm 10V$ $R_L \ge 2k$ , $V_0 = \pm 10V$		3.0 1.0		2.0 0.7		5,6 5,6	V/μV V/μV
V <sub>OUT</sub>	Maximum Output Voltage Swing	R <sub>L</sub> ≥2k		±12.5		±12.0		5,6	V
SR	Slew Rate	R <sub>L</sub> ≥2k	2	2.3		2.0		8A, 8B	V/µs
Is	Supply Current per Amplifier				3.25		3.25	2,3	mA

Note 1: The inputs are protected by back-to-back diodes. Current limiting resistors are not used in order to achieve low noise. If differential input voltage exceeds ±1.4V, the input current should be limited to 25mA.

Note 2: Siew rate is measured in  $A_V = -1$ ; input signal is  $\pm 7.5$ , output measured at  $\pm 2.5$ V.

Note 3: 0.1Hz to 10Hz noise can be inferred from the 10Hz noise voltage density test. See the test circuit and frequency response curve for 0.1Hz to 10Hz tester in the Applications Information section of the LT1007 or LT1028 data sheets.

Note 4: This parameter guaranteed by CMRR test.

## TABLE 2: ELECTRICAL TEST REQUIREMENTS

MIL-STD-883 TEST REQUIREMENTS	SUBGROUP		
Final Electrical Test Requirements (Method 5004)	1*,2,3		
Group A Test Requirements (Method 5005)	1,2,3		
Group C and D End Point Electrical Parameters (Method 5005)	1,2,3		

<sup>\*</sup> PDA Applies to subgroup 1. See PDA Test Notes.

#### PNA Test Notes

The PDA is specified as 5% based on failures from group A, subgroup 1, tests after cooldown as the final electrical test in accordance with method 5004 of MIL-STD-883 Class B. The verified failures of group A, subgroup 1, after burn-in divided by the total number of devices submitted for burn-in in that lot shall be used to determine the percent for the lot.

Linear Technology Corporation reserves the right to test to tighter limits than those given.

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